



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>09769451</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>WAKAI ET AL.</p>
	<p>Examiner</p> <p>Nguyen, Jennifer T</p>	<p>Art Unit</p> <p>2629</p>


Class	SubClass	Date	Examiner
345	157,158,173-178	8/16/06	JN

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------

Interference Searched 	Application/Control No. 09769451	Applicant(s)/Patent Under Reexamination WAKAI ET AL.
	Examiner Nguyen, Jennifer T	Art Unit 2629

Class	SubClass	Date	Examiner
718	18.01-18.03, 19	8/16/06	JN

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------

Search Notes 	Application/Control No. 09769451	Applicant(s)/Patent Under Reexamination WAKAI ET AL.
	Examiner Nguyen, Jennifer T	Art Unit 2629

Notes	Date	Examiner
East search, PAJ search, claim interference search	8/16/06	JN
U.S. Patent and Trademark Office		Part of Paper No.: